

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S11 0	0 <u>CL.6</u>	((FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and ((control near2 signal with ("at the same time" concurr\$5 simultaneous\$3 coincident coinciding) with ((programmable configurable) near2 (block element cell module))) and (routing interconnect tracks))).clm.	US-PGPUB	OR	ON	2008/02/05 14:14

Interference Search History
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EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S110	0	((FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and ((control near2 signal with ("at the same time" concurr\$5 simultaneous\$3 coincident coinciding) with ((programmable configurable) near2 (block element cell module))) and (routing interconnect tracks))).clm.	US-PGPUB	OR	ON	2008/02/05 14:14
S109	10	(LIEN-JUNG-CHEUN.in. SUN-CHUNG-YUAN.in. LIU-TONG.in. ZHANG-ZILI.in. FENG-SHENG.in. HUANG-EDDY.in. LIAO-NAIHUI.in. "ACTEL CORPORATION".as.) and ((control near2 signal) and FPGA).clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 14:00
S108	21	09/654240	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 13:33
S107	0	10/066539	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 13:30
S106	1	"7103813".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:38
S105	1	"7124338".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:34
S104	1	"6933747".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:32
S103	1	"6650141".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:26
S102	0	EP0568737	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 12:19
S101	0	"EP0568737".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 12:19

EAST Search History

S100	2	"7249335".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 12:15
S99	2	"7219280".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 12:13
S98	1	"6157210".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:04
S97	1	"6691267".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:04
S96	1	"6775817".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:03
S95	1	"6817006".PN.	USPAT; USOCR	OR	ON	2008/02/05 12:03
S94	2	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) same (test\$3 near5 rout\$3) and ("global control signal")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:58
S93	0	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) same (test\$3 near5 rout\$3) and (simultaneous\$2 near3 turn\$3 near2 on with ((programmable configurable) near2 (block element cell)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:57
S92	0	S91 and simultaneous\$2 near3 tun\$3 near2 on with ((programmable configurable) near2 (block element cell))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:56
S91	97	S88 and S90	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:53
S90	227	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) same (test\$3 near5 rout\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:53

EAST Search History

S89	2046	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (test\$3 near5 rout\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:52
S88	10484	(714/724,725,733,736 716/16 395/500.17 326/16,38-41).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/02/05 11:51
S87	17	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (((interface "input/output" "I/O") near (cell unit group)) same ((plurality multiple (more adj than adj one) (one adj "or" adj more)) near3 (mux\$3 mutlplex\$3 selector)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 15:00
S72	218	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (((interface "input/output" "I/O") near (cell unit group)) same ((plurality multiple more adj than adj one many few) with (mux\$3 mutlplex\$3 select\$3)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 14:59
S86	1	"5977793".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:55
S85	1	"6181162".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:53
S84	1	"6211697".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:51
S83	1	"5880598".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:36
S82	1	"6084429".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:36
S81	1	"6154049".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:36
S80	1	"6184709".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:35
S79	1	"6211697".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:35
S78	1	"6346824".PN.	USPAT; USOCR	OR	ON	2007/06/29 14:32

EAST Search History

S77	35	("5451887" "5455525" "5477165" "5570041" "5606267" "5625301" "5698992" "5761099" "6211697" "6380759" "6448808" "6476636" "6504398" "6700404" "6731133" "6800884" "7053653").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 14:18
S76	6	("6002268" "6191611" "6751723").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 14:18
S73	51	(714/724,725,733,736 716/16 395/500.17 326/16,38-41).ccls. and S72	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 14:16
S75	37	("20010021191" "20010028659" "20020039364" "20020061028" "20020141397" "20020163922" "20020176431" "20030031193" "20030035427" "20030053470" "20030058880" "20030165151" "6351466" "6563837" "6570873" "6667984" "6915372" "6940851").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 14:03
S74	2	"6191611".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 14:03
S66	9184	(714/724,725,733,736 716/16 395/500.17 326/16,38-41).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 13:49
S71	1478	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (((interface "input/output" "I/O") near (cell unit group))) same (mux\$3 mutlplex\$3 select\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 13:47
S23	39	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and ((interface near group) same (mux\$3 mutlplex\$3 select\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/06/29 13:42

EAST Search History

S70	4	((bridg\$3 near2 fault) with (rout\$3 interconnect tracks nets lines)) and (FPGA or field\$1programmable\$1gate\$1array))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 12:48
S56	174	((test\$3 fault) with (rout\$3 interconnect tracks) with (FPGA or field\$1programmable\$1gate\$1array))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 12:47
S69	1	"6933747".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:26
S68	1	"6996758".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:24
S67	2	S66 and S56 and (((adjacent adjoin\$3) near4 (tracks interconnect cell lines)) with ((opposite different) near3 (states value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 12:19
S59	2	S56 and (((adjacent adjoin\$3) near4 (tracks interconnect cell lines)) with ((opposite different) near3 (value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 12:18
S49	5457	(714/724,725,733,736 716/16 395/500.17).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 12:09
S65	1	"5570041".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:05
S64	1	"5621337".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:04
S63	1	"5675589".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:04
S62	1	"5818255".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:03
S61	1	"6201408".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:03
S60	1	"6239611".PN.	USPAT; USOCR	OR	ON	2006/10/11 12:01
S58	2	S56 and (((adjacent adjoin\$3) near4 (tracks interconnect cell)) with ((opposite different) near3 (value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:53

EAST Search History

S57	0	S56 and ((test near3 signal) with ((adjacent adjoin\$3) near4 (tracks interconnect cell)) with ((opposite different) near3 (value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:51
S52	0	S51 and ((test near3 signal) with ((adjacent adjoin\$3) near4 (tracks interconnect cell)) with ((opposite different) near3 (value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:48
S51	39	((test\$3 fault) with (rout\$3 interconnect tracks) with (FPGA or field\$1programmable\$1gate\$1array).clm,ab,ti.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:47
S55	4	S51 and ((adjacent adjoin\$3) near4 (tracks interconnect cell))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:41
S54	0	S51 and (((adjacent adjoin\$3) near4 (tracks interconnect cell)) with ((opposite different) near3 (value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:41
S53	0	S51 and ((test near3 signal) same ((adjacent adjoin\$3) near4 (tracks interconnect cell)) with ((opposite different) near3 (value bias voltage logic)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:40
S7	67	((test\$3 near5 rout\$3) same (FPGA or field\$1programmable\$1gate\$1array))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/10/11 11:35
S50	7	S49 and ((test\$3 near5 rout\$3) same (FPGA or field\$1programmable\$1gate\$1array)) and (global master) near3 (reset control)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 13:27
S39	7	S38 and (global master) near3 (reset control)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 13:27
S37	5220	(714/724,725,733,736 716/16 395/500.17).cccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/05/10 13:26

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S48	33	S47 and (FPGA or field\$1programmable\$1gate\$1array)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/03 15:46
S47	262	((global near3 (signal rout\$3)) with simultaneous\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/03 15:46
S46	722	((global near3 (signal rout\$3)) same simultaneous\$2)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/03 15:46
S38	28	S37 and ((test\$3 near5 rout\$3) same (FPGA or field\$1programmable\$1gate\$1array))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/03 15:46
S40	1457	S37 and simultaneous\$2	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/03 15:36
S35	4951	(714/724,725,733,736 716/16 395/500.17).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/11/03 15:24
S36	2	S35 and (FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and ((input near3 (mux mutliplexer mutliplexor)) same pad)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/05 15:21
S32	66	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and ((input near3 (mux mutliplexer mutliplexor)) same pad)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/05 15:21
S1	4617	(714/724,725,733,736 716/16 395/500.17).ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/05 15:20
S34	1	"6181162".PN.	USPAT; USOCR	OR	ON	2005/04/05 14:35

EAST Search History

S33	1	"6211697".PN.	USPAT; USOCR	OR	ON	2005/04/05 14:35
S31	1304	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (input near3 (mux mutliplexer mutliplexor))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 16:10
S30	1433	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (input near3 (mux\$3 mutliplex\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 16:09
S29	12126	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (input near3 (mux\$3 mutliplex\$3 select\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 16:09
S28	7	S27 and (mux\$3 mutliplex\$3 select\$3)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 16:03
S27	26	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and Stroud-C\$. in.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 16:02
S26	1	"5323069".PN.	USPAT; USOCR	OR	ON	2005/02/16 15:53
S25	1	"6292021".PN.	USPAT; USOCR	OR	ON	2005/02/16 15:50
S24	1	"6611153".PN.	USPAT; USOCR	OR	ON	2005/02/16 15:49
S22	11379	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic) or (gate near3 array)) and (interface same (mux\$3 mutliplex\$3 select\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 15:42
S21	11379	(FPGA or field\$1programmable\$1gate\$1array or (programmable near3 logic or (gate near3 array))) and (interface same (mux\$3 mutliplex\$3 select\$3))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 15:41

EAST Search History

S2	12	(S1 and (((test\$3 same (rout\$3 or interconnect)) same (FPGA or field\$1programmable\$1gate\$1array))) and expected and compare)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/16 15:38
S14	41	(((test\$3 same (rout\$3 or interconnect)) same (FPGA or field\$1programmable\$1gate\$1array))) and expected and compare	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/23 13:05
S20	4	("5991907" "6003150").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 15:25
S19	2	"09109123"\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 14:58
S18	0	09109123-\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 14:58
S17	0	("5991907" "6003150").pn. and US-09109123-\$.did.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 14:58
S15	35	(((test\$3 same (rout\$3 or interconnect)) same (FPGA or field\$1programmable\$1gate\$1array))) and expected and compare) not ((US-6725442-\$ or US-6470485-\$ or US-6108806-\$ or US-6668237-\$ or US-6651238-\$ or US-6347387-\$). did.)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 14:56
S16	6	"6108806".URPN.	USPAT	OR	ON	2004/06/22 14:52
S11	33	(((test\$3 same rout\$3) same (FPGA or field\$1programmable\$1gate\$1array))) and expected and compare	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 14:36
S13	4	((US-6725442-\$ or US-6470485-\$ or US-6108806-\$ or US-6668237-\$ or US-6651238-\$ or US-6347387-\$). did.) and "AND"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/22 13:33

EAST Search History

S12	6	(US-6725442-\$ or US-6470485-\$ or US-6108806-\$ or US-6668237-\$ or US-6651238-\$ or US-6347387-\$). did.	USPAT	OR	OFF	2004/06/22 13:32
S10	201	((test\$3 same rout\$3) same (FPGA or field\$1programmable\$1gate\$1array))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:52
S9	14	((test\$3 near5 rout\$3) same (FPGA or field\$1programmable\$1gate\$1array))) and expected and compare	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:52
S8	9	((test\$3 near5 rout\$3) same (FPGA or field\$1programmable\$1gate\$1array))) and (control near5 (signal pulse)) and expected and compare	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:40
S6	2	((("5469003" "5483178" "5485103" "5491353" "5504439" "5521529" "5528176" "5537057" "5541530" "5570041" "5598109" "5606266" "5606267" "5614840" "5617042" "5668771" "5671432" "5682107" "5689195" "5761099" "5764583" "5828229" "5977793" "6181162" "6211697").pn.) and ((test\$3 near5 rout\$3) same (FPGA or field\$1programmable\$1gate\$1array)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:33
S5	2	((("5469003" "5483178" "5485103" "5491353" "5504439" "5521529" "5528176" "5537057" "5541530" "5570041" "5598109" "5606266" "5606267" "5614840" "5617042" "5668771" "5671432" "5682107" "5689195" "5761099" "5764583" "5828229" "5977793" "6181162" "6211697").pn.) and ((test\$3 near5 routing) same (FPGA or field\$1programmable\$1gate\$1array)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:32
S4	47	("5469003" "5483178" "5485103" "5491353" "5504439" "5521529" "5528176" "5537057" "5541530" "5570041" "5598109" "5606266" "5606267" "5614840" "5617042" "5668771" "5671432" "5682107" "5689195" "5761099" "5764583" "5828229" "5977793" "6181162" "6211697").pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:28

EAST Search History

S3	2	"6476636".pn.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/06/21 16:26
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